PCN Number: 20200127000.1						PCN Da	ate:	Fe	eb. 18, 2020
Title: Qualification of new Mold & Mount Compound for Select Devices									
Customer Contact: PCN Manager Dept: Quality Services									
Proposed 1 <sup>st</sup> Ship Date: May 1		18, 2020		Es	•				
Change Type:									
Assembly Site				Design Wafer Bump Site			· · · · · · · · · · · · · · · · · · ·		
Assembly Process			Щ	Data Sheet		Wafer Bump Material			
Assembly Materials			Part number change			Wafer Bump Process			
Mechanical Specification				Test Site			Wafer Fab Site		
Packing/Shipping/Labeling			Test Process			Wafer Fab Materials			
			PCN Details			r rab Process			
Description of Chan	201			PCN	Details				
Description of Change:  Texas Instruments is pleased to announce the qualification of a new mount and mold compound							nd mold compound		
for the devices in the					•		w mou	nt a	na moia compouna
Group 1 device:	roduc	. /	.cu .	occion i	ociow as ion				
	Cur			it		New			
Mount Compound		14000				1400160111			
Mold Compound 18003			331	31G1 180082310F			)F		
Group 2 devices									
Group 2 device:			rrent		New				
Mount Compound					14	1400153112			
Mold Compound				00008131		18008231U1			
Reason for Change:									
Continuity of supply.									
Current mount compound and mold compound material is no longer available.									
Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):									
None									
Anticipated impact on Material Declaration									
☐ No Impact to the	•			laterial Declarations or Product Content reports are driven from					
Material Declarati	on		oduction data and will be available following the production						
			•	Upon production release the revised reports can be from the TI ECO website.					
Changes to product identification resulting from this PCN:									
None									
Product Affected: Group 1									
LM97593VH/NOPB									
Product Affected: Group 2									
DP83848VYB/NOPB         DP83848YB/NOPB         DP83848YBX/NOPB									
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## **Qualification Report**

Approve Date 16-Jan-2020

## **Qualification Results**

Data Displayed as: Number of lots / Total sample size / Total failed

Туре	Test Name / Condition	Duration	Qual Device: DP83848YB/NOPB	Qual Device: LM97593VH/NOPB
PC	Preconditioning	Level 3 - 245C	-	3/924/0
PC	Preconditioning	Level 3 - 260C	3/693/0	-
AC	Autoclave, 121C	96 Hours	3/231/0	3/231/0
BHAST	Biased HAST, 110C	264 Hours	-	3/231/0
HTSL	High Temp. Storage Bake, 150C	1000 Hours	3/231/0	3/231/0
TC	Temperature Cycle, - 65C/150C	500 Cycles	3/224/0	3/231/0
ED	Electrical Characterization	Per Datasheet Parameters	3/90/0	3/90/0
SD	Solderability, Pb	Steam age, 8 Hours	3/66/0	3/66/0
SD	Solderability, Pb-Free	Steam age, 8 Hours	3/66/0	3/66/0
MQ	Manufacturability	Per mfg. site specification	3/Pass	3/Pass
DS	Die Shear	Die	3/30/0	3/30/0
PD	Physical Dimensions	Per mechanical drawing	3/15/0	3/15/0
LFA	Lead Finish Adhesion	Leads, min. 3 units	3/45/0	3/45/0
YLD FTY and Bin Summary		-	3/Pass	3/Pass

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1000 Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1000 Hours, and 170C/420 Hours
- The following are equivalent Temperature Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

## Green/Pb-free Status:

Qualified Pb-Free (SMT) and Green

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

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USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
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